Solutions

Examination in Integrated A/D and D/A Converters, ETI220

14.00-19.00, Friday, August 27, 2010

- I. Basic questions about converters
 - a) Sampling frequency: $f_s = \frac{2^{15}}{10^{-2}} \approx 3.28 MHz$

Highest frequency: $f_{Nyq} = \frac{f_s}{2} \approx 1.64 MHz$

- b) See textbook and lectures.
- c) Quantization noise, kT/C noise, jitter.
- d) Mapping of s-domain to z-domain for $z = e^{sT}$
- e) If the amplitude of the suspected distortion is much higher than the noise floor, it is distortion. Otherwise, increasing the number of samples yields a decrease of the noise floor (if done correctly), while the amplitude of a distortion signal is not affected.
- f) A Delta-Sigma converter
- II. Specific questions about converters
 - a) See textbook and lectures.
 - b) A capacitive DAC with capacitive attenuator (see textbook and lectures).
 - c) See textbook and lectures.

d) Calculations:

$$U - V \left[\left(\frac{1}{z - 1} \right)^2 + \frac{2}{z - 1} \right] + U + E = V$$

$$V = U + 1 - z^{-1} \stackrel{2}{\to} E \rightarrow 2^{\text{nd}} \text{ order}$$

$$X_2 = U - V \left(\frac{1}{z - 1} \right)^2 = -z^{-2}E$$

- e) A folding converter. See textbook and lectures.
- f) See lecture.
- g) The negative part of the wave is quantized in exactly the same way as the positive part. This means that the q-noise samples in the negative part is perfectly correlated to the q-noise in the positive part. More specifically, for each q-error sample in the positive part there is the same q-error sample (with inverted sign) in the negative part. Thus, all even bins are empty, and the q-noise is found only in the odd bins.